TOSHIBA CMOS Didital Integrated Circuit   Silicon Monolithic

TC7MET240AFK,TC7MET244AFK

Octal Bus Buffer

TC7MET240AFK Inverted, 3-State Outputs

TC7MET244AFK Non-Inverted, 3-State Outputs

   The TC7MET240AFK and 244AFK are advanced high speed CMOS octal bus buffers fabricated with silicon gate C^2MOS technology. They achieve the high speed operation similar to equivalent bipolar schottky TTL while maintaining the CMOS low power dissipation.

   The TC7MET240AFK is an inverting 3-state buffer having two active-low output enables. TC7MET244AFK is a non-inverting 3-state buffer, and has two active-low output enables.

   These devices are designed to be used with 3-state memory address drivers, etc.

   The input voltage are compatible with TTL output voltage.
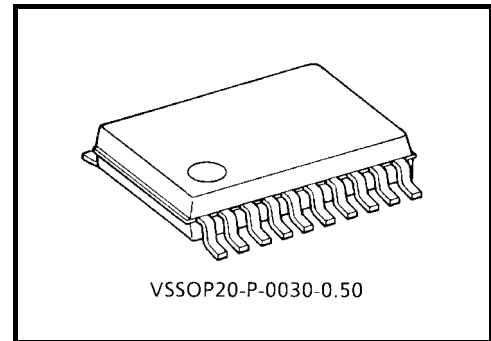
   These devices may be used as a level converter for interfacing 3.3 V to 5 V system.

   Input protection and output circuit ensure that 0 to 5.5 V can be applied to the input and output [Note] pins without regard to the supply voltage. These structure prevents device destruction due to mismatched supply and input/output voltages such as battery back up, hot board insertion, etc.
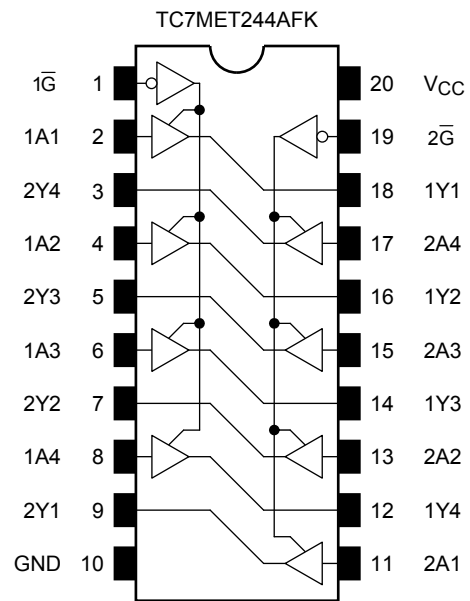
   Note: V_{CC} = 0 V

VSSOP20-P-0030-0.50

Weight: 0.03 g (typ.)

Features

- High speed: t_{pd} = 5.6 ns (typ.) (V_{CC} = 5 V)
- Low power dissipation: I_{CC} = 4 μA (max) (Ta = 25°C)
- Compatible with TTL outputs: V_{IL} = 0.8 V (max)

   V_{IH} = 2.0 V (min)

- Power down protection is provided on all inputs and outputs.
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Low noise: V_{OLP} = 1.0 V (max)
- Pin and function compatible with the 74 series (74AC/HC/F/ALS/LS etc.) 240/244 type.

Pin Assignment (top view)

TC7MET240AFK

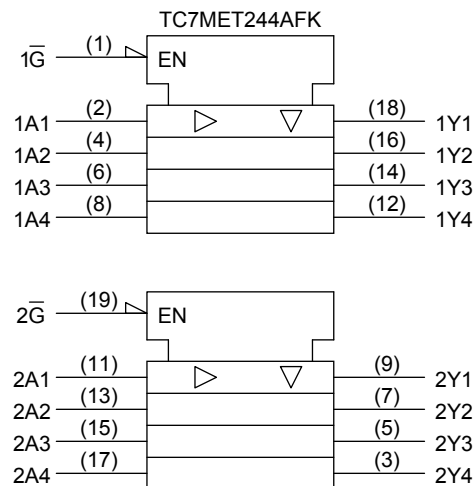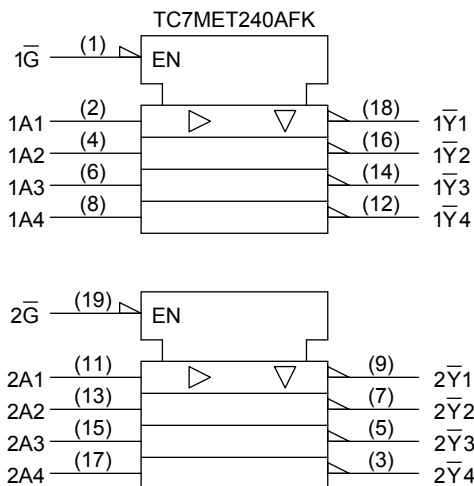| Pin	Signal		Pin	Signal
1	$1\overline{G}$		20	V_{CC}
2	1A1		19	$2\overline{G}$
3	$2\overline{Y}4$		18	$1\overline{Y}1$
4	1A2		17	2A4
5	$2\overline{Y}3$		16	$1\overline{Y}2$
6	1A3		15	2A3
7	$2\overline{Y}2$		14	$1\overline{Y}3$
8	1A4		13	2A2
9	$2\overline{Y}1$		12	$1\overline{Y}4$
10	GND		11	2A1

TC7MET244AFK

Pin	Signal		Pin	Signal
1	$1\overline{G}$		20	V_{CC}
2	1A1		19	$2\overline{G}$
3	2Y4		18	1Y1
4	1A2		17	2A4
5	2Y3		16	1Y2
6	1A3		15	2A3
7	2Y2		14	1Y3
8	1A4		13	2A2
9	2Y1		12	1Y4
10	GND		11	2A1

IEC Logic Symbol

TC7MET240AFK

$1\overline{G}$ (1) EN

1A1	(2)		(18)	$1\overline{Y}1$
1A2	(4)		(16)	$1\overline{Y}2$
1A3	(6)		(14)	$1\overline{Y}3$
1A4	(8)		(12)	$1\overline{Y}4$

$2\overline{G}$ (19) EN

2A1	(11)		(9)	$2\overline{Y}1$
2A2	(13)		(7)	$2\overline{Y}2$
2A3	(15)		(5)	$2\overline{Y}3$
2A4	(17)		(3)	$2\overline{Y}4$

TC7MET244AFK

$1\overline{G}$ (1) EN

1A1	(2)		(18)	1Y1
1A2	(4)		(16)	1Y2
1A3	(6)		(14)	1Y3
1A4	(8)		(12)	1Y4

$2\overline{G}$ (19) EN

2A1	(11)		(9)	2Y1
2A2	(13)		(7)	2Y2
2A3	(15)		(5)	2Y3
2A4	(17)		(3)	2Y4

Truth Table

Inputs		Outputs	
$\overline{G}$	A_n	Y_n	$\overline{Y}_n$
L	L	L	H
L	H	H	L
H	X	Z	Z

X: Don't care

Z: High impedance

Y_n: TC7MET244AFK

$\overline{Y}_n$: TC7MET240AFK

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating		Unit
Supply voltage range	V_{CC}	−0.5~7.0		V
DC input voltage	V_{IN}	−0.5~7.0		V
DC output voltage	V_{OUT}	−0.5~7.0 (Note 2)		V
		−0.5~V_{CC} + 0.5 (Note 3)		
Input diode current	I_{IK}	−20		mA
Output diode current	I_{OK}	±20 (Note 4)		mA
DC output current	I_{OUT}	±25		mA
DC V_{CC}/ground current	I_{CC}	±75		mA
Power dissipation	P_D	180		mW
Storage temperature	T_{stg}	−65~150		°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I_{OUT} absolute maximum rating must be observed.

Note 4: $V_{OUT} < GND$, $V_{OUT} > V_{CC}$

Operating Ranges (Note 1)

Characteristics	Symbol	Rating		Unit
Supply voltage	V_{CC}	4.5~5.5		V
Input voltage	V_{IN}	0~5.5		V
Output voltage	V_{OUT}	0~5.5 (Note 2)		V
		0~V_{CC} (Note 3)		
Operating temperature	T_{opr}	−40~85		°C
Input rise and fall time	dt/dv	0~20		ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.

Note 2: Output in off-state

Note 3: High or low state

Electrical Characteristics

DC Characteristics

Characteristics		Symbol	Test Condition		V_{CC} (V)	Ta = 25°C			Ta = −40~85°C		Unit
						Min	Typ.	Max	Min	Max	
Input voltage	High level	V_{IH}	—		4.5~5.5	2.0	—	—	2.0	—	V
	Low level	V_{IL}	—		4.5~5.5	—	—	0.8	—	0.8	
Output voltage	High level	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50$ μA	4.5	4.4	4.5	—	4.4	—	V
				$I_{OH} = -8$ mA	4.5	3.94	—	—	3.80	—	
	Low level	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 50$ μA	4.5	—	0	0.1	—	0.1	
				$I_{OL} = 8$ mA	4.5	—	—	0.36	—	0.44	
3-state output off-state current		I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = V_{CC}$ or GND		5.5	—	—	±0.25	—	±2.50	μA
Input leakage current		I_{IN}	$V_{IN} = 5.5$ V or GND		0~5.5	—	—	±0.1	—	±1.0	μA
Quiescent supply current		I_{CC}	$V_{IN} = V_{CC}$ or GND		5.5	—	—	4.0	—	40.0	μA
		I_{CCT}	Per input: $V_{IN} = 3.4$ V Other input: V_{CC} or GND		5.5	—	—	1.35	—	1.50	mA
Output leakage current		I_{OPD}	$V_{OUT} = 5.5$ V		0	—	—	0.5	—	5.0	μA

AC Characteristics (Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition		V_{CC} (V)	C_L (pF)	Ta = 25°C			Ta = −40~85°C		Unit
						Min	Typ.	Max	Min	Max	
Propagation delay time (TC7MET240AFK)	t_{pLH} t_{pHL}	—		5.0 ± 0.5	15	—	5.6	7.8	1.0	9.0	ns
					50	—	6.1	8.8	1.0	10.0	
Propagation delay time (TC7MET244AFK)	t_{pLH} t_{pHL}	—		5.0 ± 0.5	15	—	5.4	7.4	1.0	8.5	ns
					50	—	5.9	8.4	1.0	9.5	
3-state output enable time	t_{pZL} t_{pZH}	$R_L = 1$ kΩ		5.0 ± 0.5	15	—	7.7	10.4	1.0	12.0	ns
					50	—	8.2	11.4	1.0	13.0	
3-state output disable time	t_{pLZ} t_{pHZ}	$R_L = 1$ kΩ		5.0 ± 0.5	50	—	8.8	11.4	1.0	13.0	ns
Output to output skew	t_{osLH} t_{osHL}	(Note 1)		5.0 ± 0.5	50	—	—	1.0	—	1.0	ns
Input capacitance	C_{IN}	—				—	4	10	—	10	pF
Output capacitance	C_{OUT}	—				—	9	—	—	—	pF
Power dissipation capacitance (Note 2)	C_{PD}	TC7MET240AFK				—	19	—	—	—	pF
		TC7MET244AFK				—	18	—	—	—	

Note 1: Parameter guaranteed by design.

$t_{osLH} = |t_{pLHm} − t_{pLHn}|$, $t_{osHL} = |t_{pHLm} − t_{pHLn}|$

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$ (per bit)

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Noise Characteristics (Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Ta = 25°C Typ.	Ta = 25°C Limit	Unit
Quiet output maximum dynamic V_{OL}	V_{OLP}	$C_L = 50$ pF	5.0	0.8	1.0	V
Quiet output minimum dynamic V_{OL}	V_{OLV}	$C_L = 50$ pF	5.0	−0.8	−1.0	V
Minimum high level dynamic input voltage V_{IH}	V_{IHD}	$C_L = 50$ pF	5.0	—	2.0	V
Maximum high level dynamic input voltage V_{IL}	V_{ILD}	$C_L = 50$ pF	5.0	—	0.8	V

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Package Dimensions

VSSOP20-P-0030-0.50   Unit : mm
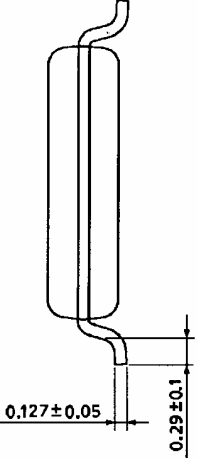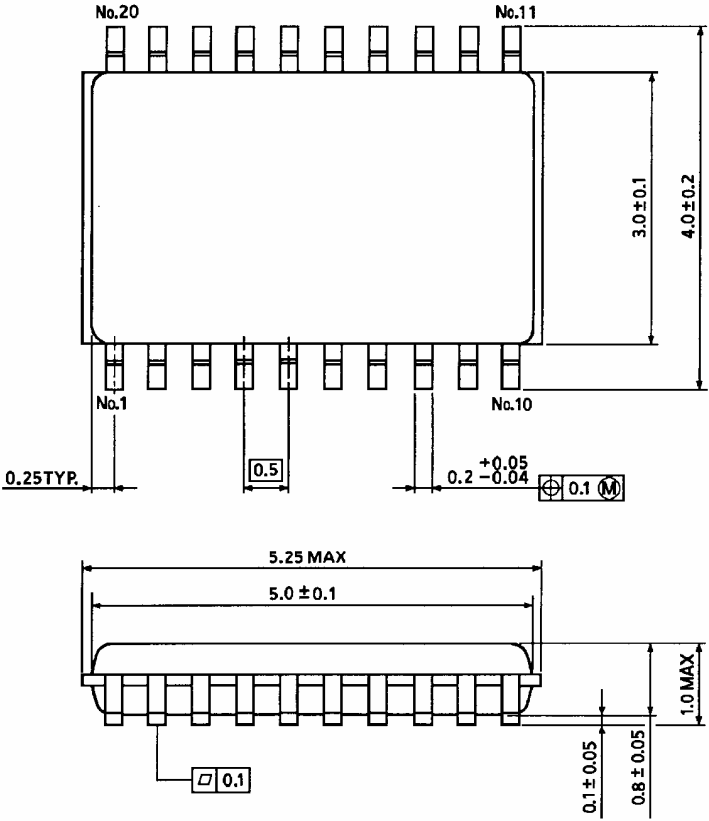
Weight: 0.03 g (typ.)

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